

Notice of References Cited

Application/Control No.

09/943,690

Applicant(s)/Patent Under

Reexamination

WEIER ET AL.

Examiner

Tae H. Yoon

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,245,070	01-1981	Kemp, Thomas	526/75
	B	US-6,245,848	06-2001	Espiard et al.	524/419
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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